1

LINEAR INTEGRATED CIRCUITS

DESCRIPTION

The 526 is a high speed analog comparator intended for use in systems where low propagation delay and fast recovery from common mode or differential input overdrive is required. The device is specifically designed to provide a wide input common mode range while operating from power supplies commonly found in digital logic systems.

The 526 consists of a medium gain, high frequency differential amplifier and a high speed TTL gate fabricated within a single substrate by planar and epitaxial techniques. The output gate of the 526 has voltage and current capabilities compatible with DCL, DTL and TTL. The 526 output gate has a full fan-out of 10 to standard TTL loads.

The amplifier and gate may be used independently or cascaded for applications as a voltage comparator, digital line receiver or sense amplifier. The second gate input is used to provide strobe capability when operating the amplifier and gate in cascade.

FEATURES

•	AGA	MOUT	DEI	ΔV

30ns

INPUT COMMON MODE RANGE

+4.5V -3.5V

DIFFERENTIAL OVERDRIVE RECOVERY

20ns

OUTPUT COMPATIBLE WITH

STANDARD LOGIC FORMS

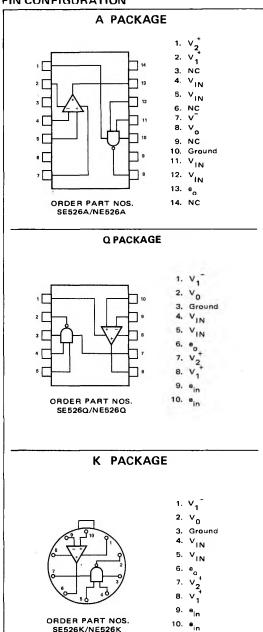
OPERATES FROM STANDARD ±5V SUPPLIES

APPOLUTE MAXIMUM RATINGS

Supply Voltage	+7.0V			
Gate Input Voltage	+6.0V			
Differential Input Voltag	+5.0V			
Common Mode Input Vo	+5.0V			
Gate Output Current	+100 mA			
Storage Temperature		-65°C to +150°C		
Operating Temperature	SE526 NE526	-55°C to +125°C 0°C to +75°C		

Absolute Maximum Ratings are limiting values above which serviceability may be impaired.

PIN CONFIGURATION



SE526K/NE526K

LECTRICAL CHARACTERISTICS (Standard Conditions: $V_1^+ = V_2^+ = 5.0V$, $V^- = -5.0V$; Notes 1,2,3,4,13,14)

CHARACTERISTIC	SYMBOL	LIMITS				TEMPERATURE		NOTES
		MIN.	TYP.	MAX.	UNIT	SE526	NE526	7
Input Offset Voltage	Vio Vio Vio		2.0 2.0 2.0	5.0 5.0 5.0	m∨ m∨ m∨	- 55° C +25° C +125° C	0° C +25° C +75° C	5 5 5
Input Bias Current	lin lin lin		30.0 25.0 22.0	35.0 35.0 35.0	μΑ μΑ μΑ	- 55° C +25° C +125° C	0°C +25°C +75°C	6 6 6
Input Offset Current	lio lio lio	40	0.6 0.5 0.4	5.0 5.0 5.0	μΑ μΑ μΑ	- 55° C +25° C +125° C	0° C +25° C +75° C	
Input Common Mode Range	Vcm Vcm Vcm Vcm Vcm Vcm	44.2 +4.2 +4.2 -3.2 -3.2 -3.2	+4.7 +4.5 +4.4 -3.5 -3.5 -3.5		>>>>	- 55° C +25° C +125° C - 55° C +25° C +125° C	0° C +25° C +75° C 0° C +25° C +75° C	
Amplifier Output Voltage	Vohi Vohi Vohi Volo Volo Volo	3.5 3.5 3.5		0.6 0.5 0.4	>>>>	- 55° C +25° C +125° C - 55° C +25° C +125° C	0° C +25° C +75° C 0° C +25° C +75° C	
Amplifier Power Consumption	Pd Pd Pd		90 100 110	120 120 120	m/W m/W m/W	- 55° C +25° C +125° C	0° C +25° C +75° C	
Gate Output Voltage	V1 ₀ V1 ₀ V1 ₀ V0 ₀ V0 ₀ V0 ₀	2.8 2.8 2.8	3.5 3.2 3.0 0.3 0.2 0.3	0.4 0.4 0.4	>>>>>	- 55° C +25° C +125° C - 55° C +25° C +125° C	0° C +25° C +75° C 0° C +25° C +75° C	7,8 7,8 7,8 7,8 7,8 7,8
Gate Output Sink Current	100	16.0		1	mA	+25° C	+25° C	8
Gate Output Source Current	110	1.0			mA	+25° C	+25° C	7
Gate Input Threshold Voltage	V1; V1; V1; V0; V0; V0;	2.0 2.0 2.0		1.0 0.9 0.8	>>>>	- 55° C +25° C +125° C - 55° C +25° C +125° C	ଫ C +25° C +75° C ଫ C +25° C +75° C	9 9 10 10
Gate Input Current (Input "0")	10; 10; 10;	-0.1 -0.1 -0.1	-1.2 -1.4 -1.2 5	-1.6 -1.6 -1.6 25	mA mA mA	- 55° C +25° C +125° C - 55° C	0° C +25° C +75° C 0° C	
(input 1)	11 11		10 15	25 25 25	μA μA	+25° C +125° C	+25° C +75° C	
Gate Current Consumption (Output "1")	cc1 cc1 cc1			2.00 2.00 2.00	mA mA mA	− 55° C +25° C +125° C	0° C +25° C +75° C	
(Output "0")	1000 1000			5.00 5.00 5.00	mA mA mA	- 55° C +25° C +125° C	0° C +25° C +75° C	
Gate Input Latch Voltage Rating	BV _i			6.0	V	+25° C	+25° C	
Gate Output Short Circuit Current	Iso	-10.0		-70.0	mA	+25° C	+25° C	
Switching Times Gate Turn-On Delay Gate Turn-Off Delay Propagation Delay Propagation Delay Propagation Delay Differential Overload Recovery	Ton Toff Tod Tod Tpd1		15 15 30 40 30	17 17 42 48 40	ns ns ns ns	+25° C +25° C +25° C +25° C +25° C	+25° C +25° C +25° C +25° C +25° C	11 11 11 11 11,1

Recommended Operating Supply Voltages (V₁ + v₂ + = 5.0V, V = -5.0V

NOTES: 1. All measurements are referenced to the ground terminal.

- 2. Positive current is defined as into the pin referenced.
- 3. Pins not specifically referenced are left electrically
- open.

 4. Precautionary measures should be taken to ensure current limiting in accordance with Absolute Maximum Ratings should the legistion digdes become for-
- 5. Input Offset Voltage is tested at guaranteed Input Common Mode Range voltage limits and includes the
- worst case variations of voltage gain and input impedence. These are the maximum values required to drive the output down to "o" or up to "1".
- Input Bias Current is defined as the maximum current required to bias either input.
- 7. Output source current is supplied through £ resistor to ground.

 8. Output sink current is supplied through a resistor
- to V_2^{-1} .
 9. These limits are guaranteed by Gate Output Voltage (Vd_O) test
- 10. These limits are guaranteed by Gate Output Voltage
- (V1_O) tests.

 11 Load capacitance includes test fixture and probe capacitance.
- 12. Differential input Voltage = 500mV for this test.

 13. Acceptance Test Subgroup A-7 provides and point
- parameters for linear devices processed to Signetics
 13 SURE Program. See Signetics SURE Bulletin 5001.
- 14. Manufacturer reserves the right to make design and process changes and improvements.